

Search Notes

Application/Control No.

10/564,034

Examiner

Hau V. Phan

Applicant(s)/Patent under
Reexamination

MIYAGAWA ET AL.

Art Unit

3618

SEARCHED

Class	Subclass	Date	Examiner
180	291 274 297 784	6/22/2007	HP
	300		
	312		
248	605	6/22/2007	HP
	562		
	634		
267	140.3	6/22/2007	HP
	141.2		
296	187.09	6/22/2007	HP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR